

N-channel 650 V, 0.049 Ω 46 A MDmesh™ V Power MOSFET
in TO-247, TO-3PF

Features

Order codes	V_{DSS} @ T_{Jmax}	$R_{DS(on)}$ max	I_D
STFW60N65M5	710 V	< 0.059 Ω	46 A
STW60N65M5			

- Worldwide best $R_{DS(on)}$ * area amongst the silicon based devices
- Higher V_{DSS} rating
- High dv/dt capability
- Excellent switching performance
- Easy to drive
- 100% avalanche tested

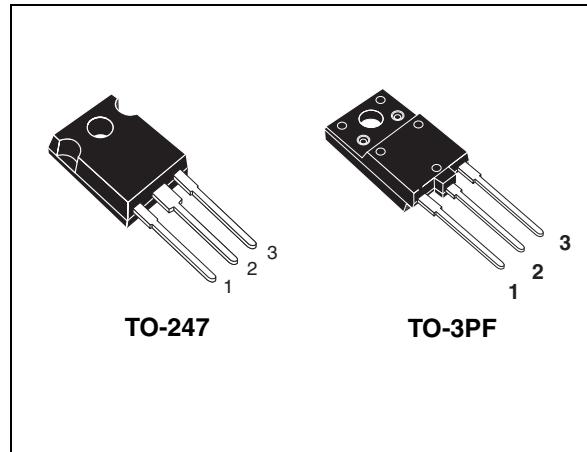
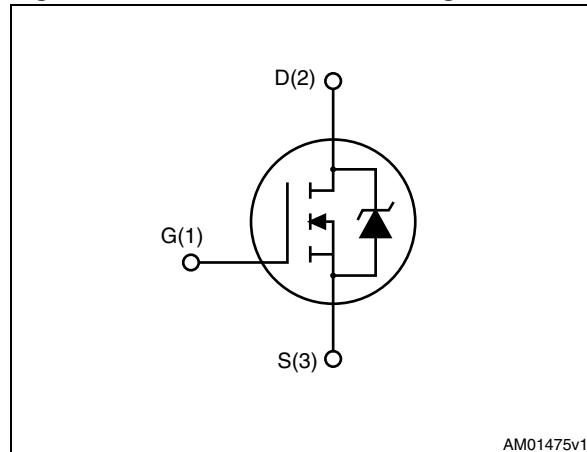


Figure 1. Internal schematic diagram



Application

Switching applications

Description

The devices are N-channel MDmesh™ V Power MOSFET based on an innovative proprietary vertical process technology, which is combined with STMicroelectronics' well-known PowerMESHTM horizontal layout structure. The resulting product has extremely low on-resistance, which is unmatched among silicon-based Power MOSFETs, making it especially suitable for applications which require superior power density and outstanding efficiency.

Table 1. Device summary

Order codes	Marking	Package	Packaging
STFW60N65M5	60N65M5	TO-3PF	Tube
STW60N65M5		TO-247	

1 Electrical ratings

Table 2. Absolute maximum ratings

Symbol	Parameter	Value		Unit
		TO-247	TO-3PF	
V_{GS}	Gate-source voltage	± 25		V
I_D	Drain current (continuous) at $T_C = 25^\circ\text{C}$	46		A
I_D	Drain current (continuous) at $T_C = 100^\circ\text{C}$	29		A
$I_{DM}^{(1)}$	Drain current (pulsed)	184		A
P_{TOT}	Total dissipation at $T_C = 25^\circ\text{C}$	255	79	W
I_{AR}	Avalanche current, repetitive or non-repetitive (pulse width limited by T_j max)	12		A
E_{AS}	Single pulse avalanche energy (starting $T_j = 25^\circ\text{C}$, $I_D = I_{AR}$, $V_{DD} = 50$ V)	1400		mJ
$dv/dt^{(2)}$	Peak diode recovery voltage slope	15		V/ns
V_{ISO}	Insulation withstand voltage (RMS) from all three leads to external heat sink ($t=1$ s; $T_c=25^\circ\text{C}$)		3500	V
T_{stg}	Storage temperature	- 55 to 150		$^\circ\text{C}$
T_j	Max. operating junction temperature	150		$^\circ\text{C}$

1. Pulse width limited by safe operating area
2. $I_{SD} \leq 46$ A, $dI/dt \leq 400$ A/ μs , $V_{DD} = 400$ V, $V_{Peak} < V_{(BR)DSS}$

Table 3. Thermal data

Symbol	Parameter	Value		Unit
		TO-247	TO-3PF	
$R_{thj-case}$	Thermal resistance junction-case max	0.49	1.58	$^\circ\text{C}/\text{W}$
$R_{thj-amb}$	Thermal resistance junction-ambient max	50		$^\circ\text{C}/\text{W}$
T_I	Maximum lead temperature for soldering purpose	300		$^\circ\text{C}$

2 Electrical characteristics

($T_C = 25^\circ\text{C}$ unless otherwise specified)

Table 4. On /off states

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$V_{(\text{BR})\text{DSS}}$	Drain-source breakdown voltage	$I_D = 1 \text{ mA}, V_{GS} = 0$	650			V
I_{DSS}	Zero gate voltage drain current ($V_{GS} = 0$)	$V_{DS} = \text{Max rating}$ $V_{DS} = \text{Max rating}, T_C = 125^\circ\text{C}$			1 100	μA μA
I_{GSS}	Gate-body leakage current ($V_{DS} = 0$)	$V_{GS} = \pm 25 \text{ V}$			100	nA
$V_{GS(\text{th})}$	Gate threshold voltage	$V_{DS} = V_{GS}, I_D = 250 \mu\text{A}$	3	4	5	V
$R_{DS(\text{on})}$	Static drain-source on resistance	$V_{GS} = 10 \text{ V}, I_D = 23 \text{ A}$		0.049	0.059	Ω

Table 5. Dynamic

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
C_{iss}	Input capacitance			6810		pF
C_{oss}	Output capacitance	$V_{DS} = 100 \text{ V}, f = 1 \text{ MHz},$ $V_{GS} = 0$	-	141	-	pF
C_{rss}	Reverse transfer capacitance			6.2		pF
$C_{o(tr)}^{(1)}$	Equivalent capacitance time related		-	480	-	pF
$C_{o(er)}^{(2)}$	Equivalent capacitance energy related	$V_{DS} = 0 \text{ to } 520 \text{ V}, V_{GS} = 0$	-	140	-	pF
R_G	Intrinsic gate resistance	$f = 1 \text{ MHz open drain}$	-	1	-	Ω
Q_g	Total gate charge	$V_{DD} = 520 \text{ V}, I_D = 23 \text{ A},$ $V_{GS} = 10 \text{ V}$		139		nC
Q_{gs}	Gate-source charge		-	34	-	nC
Q_{gd}	Gate-drain charge			52		nC

1. $C_{o(tr)}$ is a constant capacitance value that gives the same charging time as C_{oss} while V_{DS} is rising from 0 to 80% V_{DSS} .
2. $C_{o(er)}$ is a constant capacitance value that gives the same stored energy as C_{oss} while V_{DS} is rising from 0 to 80% V_{DSS} .

Table 6. Switching times

Symbol	Parameter	Test conditions	Min.	Typ.	Max	Unit
$t_d(v)$	Voltage delay time	$V_{DD} = 400 \text{ V}$, $I_D = 30 \text{ A}$,		90		ns
$t_r(v)$	Voltage rise time	$R_G = 4.7 \Omega$, $V_{GS} = 10 \text{ V}$	-	11	-	ns
$t_f(i)$	Current fall time			13	-	ns
$t_c(\text{off})$	Crossing time			16	-	ns

Table 7. Source drain diode

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
I_{SD}	Source-drain current		-		46	A
$I_{SDM}^{(1)}$	Source-drain current (pulsed)				184	A
$V_{SD}^{(2)}$	Forward on voltage	$I_{SD} = 46 \text{ A}$, $V_{GS} = 0$	-		1.5	V
t_{rr}	Reverse recovery time	$I_{SD} = 46 \text{ A}$, $dI/dt = 100 \text{ A}/\mu\text{s}$		448		ns
Q_{rr}	Reverse recovery charge	$V_{DD} = 100 \text{ V}$ (see)	-	10		μC
I_{RRM}	Reverse recovery current			45		A
t_{rr}	Reverse recovery time	$I_{SD} = 46 \text{ A}$, $dI/dt = 100 \text{ A}/\mu\text{s}$		534		ns
Q_{rr}	Reverse recovery charge	$V_{DD} = 100 \text{ V}$, $T_j = 150 \text{ }^\circ\text{C}$	-	14		μC
I_{RRM}	Reverse recovery current			52		A

1. Pulse width limited by safe operating area
2. Pulsed: pulse duration = 300 μs , duty cycle 1.5%

2.1 Electrical characteristics (curves)

Figure 2. Safe operating area for TO-3FP

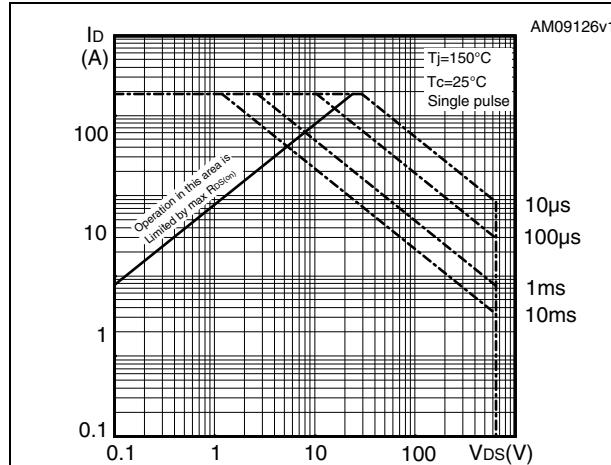


Figure 3. Thermal impedance for TO-3FP

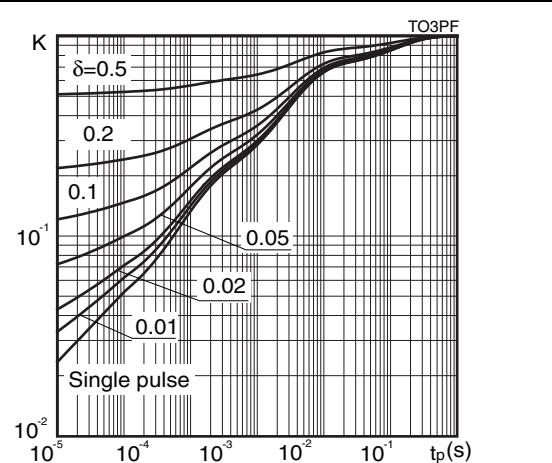


Figure 4. Safe operating area for TO-247

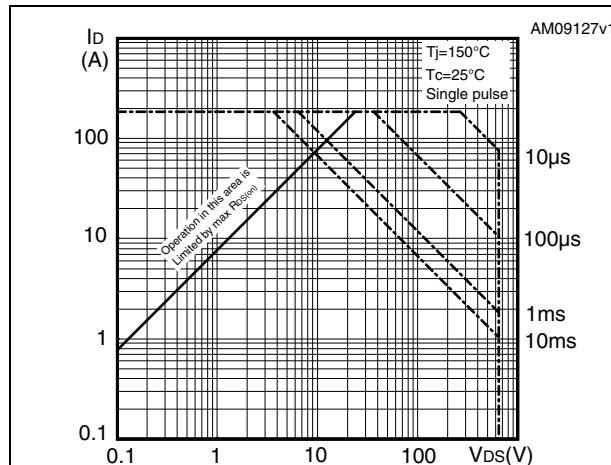


Figure 5. Thermal impedance for TO-247

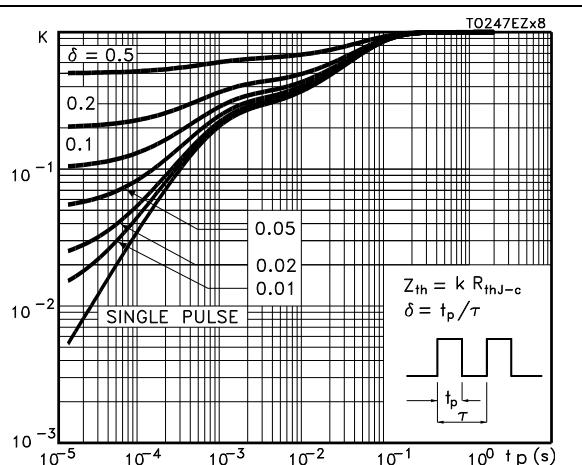


Figure 6. Output characteristics

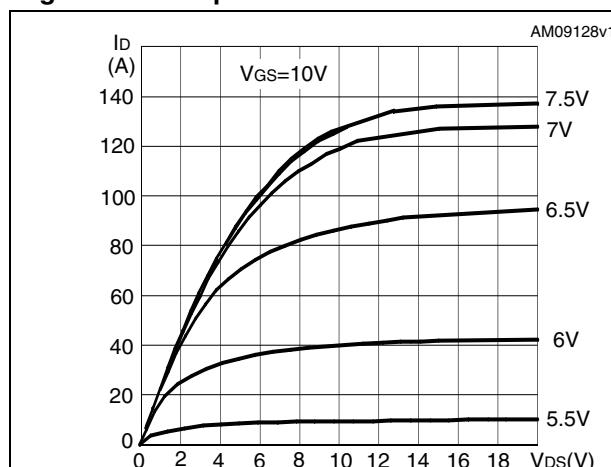


Figure 7. Transfer characteristics

